

**Notice of References Cited**

Application/Control No.

10/627,651

Applicant(s)/Patent Under  
Reexamination  
CHANG ET AL.

Examiner

Nhan T. Tran

Art Unit

2622

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,665,455	12-2003	Ting, Chih-Yu	348/373
*	B	US-7,170,665	01-2007	Kaneko et al.	359/290
*	C	US-6,943,966	09-2005	Konno, Mitsujiro	359/819
*	D	US-7,142,243	11-2006	Dobashi, Hideki	348/340
*	E	US-6,867,812	03-2005	Iizumi et al.	348/374
*	F	US-6,683,654	01-2004	Hajima, Hideki	348/374
*	G	US-2002/0140836	10-2002	Miyake et al.	348/340
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.